

DRV8801A-Q1 DMOS Full-Bridge Motor Drivers

1 Features

- Qualified for Automotive Applications
- Low ON-Resistance (0.83 Ω) Outputs
- Low-Power Sleep Mode
- 100% PWM Supported
- 6.5 to 36-V Operating Supply Voltage Range
- Thermally Enhanced Surface-Mount Package
- Configurable Overcurrent Limit
- **Protection Features**
 - V_{BB} Undervoltage Lockout (UVLO)
 - Overcurrent Protection (OCP)
 - Short-to-Supply Protection
 - Short-to-Ground Protection
 - Overtemperature Warning (OTW)
 - Overtemperature shutdown (OTS)
 - Overcurrent and Overtemperature Fault Conditions Indicated On Pin (nFAULT)

2 Applications

- Automotive Body Systems
- Door Locks
- HVAC Actuators
- Piezo Alarm

3 Description

The DRV8801A-Q1 device provides a versatile motor-driver solution with a full H-bridge driver. The device can drive a brushed DC motor or one winding of a stepper motor, as well as other devices like solenoids. A simple PHASE and ENABLE interface allows easy interfacing to controller circuits.

The output stages use N-channel power MOSFETs configured as an H-bridge. The DRV8801A-Q1 device is capable of peak output currents up to ± 2.8 A and operating voltages up to 36 V. An internal charge pump generates required gate drive voltages.

A low-power sleep mode is provided which shuts down internal circuitry to achieve very low quiescent current draw. This sleep mode can be set using a dedicated nSLEEP pin.

Internal protection functions are provided undervoltage lockout, overcurrent protection, short-to-supply protection, short-to-ground protection, overtemperature warning, and overtemperature shutdown. Overcurrent (including short-to-ground and short-to-supply) and overtemperature fault conditions are indicated via an nFAULT pin.

The DRV8801A-Q1 device is packaged in a 16-pin WQFN package with wettable flanks and exposed thermal pad (Eco-friendly: RoHS & no Sb/Br).

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
DRV8801A-Q1	WQFN (16)	4.00 mm x 4.00 mm

(1) For all available packages, see the orderable addendum at the end of the datasheet.

Simplified Application Diagram

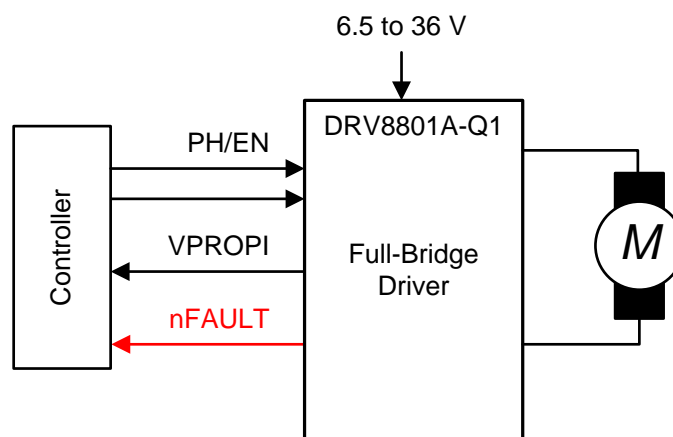


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4 Revision History

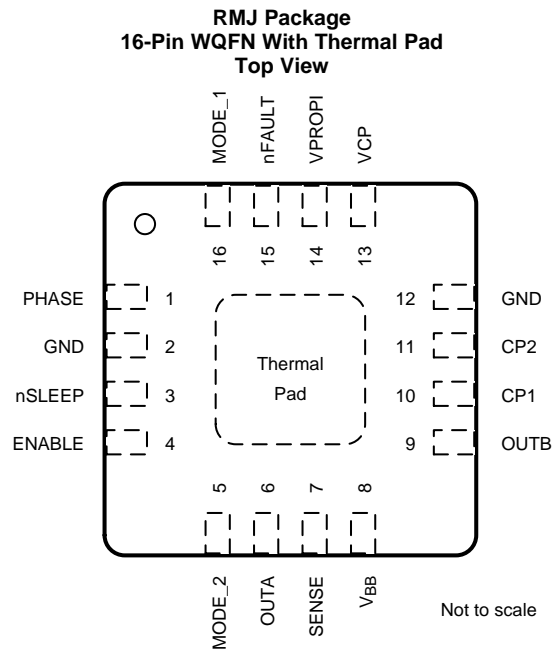
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision B (June 2016) to Revision C	Page
• Changed the T_J value for some test conditions for the output ON resistance parameter in the <i>Electrical Characteristics</i>	5
• Added the <i>Documentation Support</i> , <i>Receiving Notification of Documentation Updates</i> , and <i>Community Resources</i> sections	17

Changes from Revision A (September 2014) to Revision B	Page
• Changed the value of T_J from 125°C to 25°C in the test condition (source driver, $I_O = -2.8$ A, $V_{BB} = 8$ to 36 V) for the output ON resistance parameter	5
• Added the UVLO hysteresis parameter in the <i>Electrical Characteristics</i> table	6
• Added MIN and MAX values for the overcurrent retry time parameter in the <i>Electrical Characteristics</i> table	6
• Updated the <i>Functional Block Diagram</i>	8
• Added t_{pd} to the <i>Overcurrent Control Timing</i> image	11

Changes from Original (June 2014) to Revision A	Page
• Added TYPE column to the <i>Pin Functions</i> table	3
• Updated the <i>Overcurrent Control Timing</i> image.....	11

5 Pin Configuration and Functions



Pin Functions

PIN		TYPE	DESCRIPTION
NAME	NO.		
CP1	10	—	Charge-pump capacitor 1
CP2	11	—	Charge-pump capacitor 2
ENABLE	4	I	Enables OUTA and OUTB drivers
GND	2	PWR	Ground
	12		
MODE 1	16	I	Mode logic input
MODE 2	5	I	Mode 2 logic input
nFAULT	15	OD	Fault open-drain output. A logic low indicates fault a condition
nSLEEP	3	I	Logic low puts the device in a low-power sleep mode
OUTA	6	O	DMOS full-bridge output positive. H-Bridge output A
OUTB	9	O	DMOS full-bridge output negative. H-Bridge output B
PHASE	1	I	Phase logic input for direction control
SENSE	7	IO	Sense power return
V _{BB}	8	PWR	Driver supply voltage
VCP	13	—	Charge-pump reservoir capacitor pin
VPROPI	14	O	Winding current proportional voltage output
Thermal pad		—	Exposed pad for thermal dissipation; connect to GND pins.

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
Power supply voltage ⁽²⁾	V _{BB}	-0.3	40	V
Charge pump voltage	VCP, CP1, and CP2	-0.3	V _{BB} + 7	V
Digital pin voltage	PHASE, ENABLE, MODE1, MODE2, nSLEEP, nFAULT	-0.3	7	V
V _{BB} to OUTx voltage	OUTA and OUTB	-0.3	36	V
OUTx to GND voltage	OUTA and OUTB	-0.3	36	V
Sense pin voltage	SENSE	-0.5	0.5	V
H-bridge output current	OUTA, OUTB, and SENSE		2.8	A
VPROPI pin voltage	VPROPI	-0.3	3.6	V
Maximum junction temperature, T _J			150	°C
Storage temperature, T _{stg}		-40	125	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltage values are with respect to network ground terminal.

6.2 ESD Ratings

			VALUE	UNIT	
V _(ESD)	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 ⁽¹⁾	±2000	V	
		Charged-device model (CDM), per AEC Q100-011	All pins		±500
			Corner pins (1, 4, 5, 8, 9, 12, 13, and 16)		±750

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

		MIN	MAX	UNIT
V _{BB}	Power supply voltage	6.5	36	V
V _{CC}	Logic supply voltage	0	5.5	V
f _(PWM)	Applied PWM signal (PHASE and ENABLE)	0	100	kHz
I _O	H-bridge peak output current	0	2.8	A
T _A	Ambient temperature	-40	125	°C

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		DRV8801A-Q1	
		RMJ (WQFN)	
		16 PINS	
			UNIT
R _{θJA}	Junction-to-ambient thermal resistance	36.8	°C/W
R _{θJctop}	Junction-to-case (top) thermal resistance	43.4	°C/W
R _{θJB}	Junction-to-board thermal resistance	14.7	°C/W
ψ _{JT}	Junction-to-top characterization parameter	0.7	°C/W
ψ _{JB}	Junction-to-board characterization parameter	14.7	°C/W
R _{θJcbot}	Junction-to-case (bottom) thermal resistance	4.3	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

T_A = 25°C, over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
POWER SUPPLIES (V_{BB})								
V _{BB}	V _{BB} operating supply voltage			6.5		36	V	
I _{BB}	V _{BB} operating supply current	f _{PWM} < 50 kHz Charge pump on, Outputs disabled			6		mA	
					3.2			
I _{BB(Q)}	V _{BB} sleep-mode supply current	nSLEEP = 0, T _J = 25°C				10	μA	
CONTROL INPUTS (PHASE, ENABLE, MODE1, MODE2, nSLEEP)								
V _{IL}	Input logic low voltage	PHASE, ENABLE, MODE1, MODE2				0.8	V	
V _{IH}	Input logic high voltage			2				
I _{IL}	Input logic low current	PHASE, ENABLE, MODE1, MODE2	V _I = 0.8 V	-20	≤ -2	20	μA	
I _{IH}	Input logic high current		V _I = 2 V		< 1	20		
I _{IL}	Input logic low current	ENABLE	V _I = 0.8 V			16	μA	
I _{IH}	Input logic high current		V _I = 2 V			40		100
V _{IL}	Input logic low voltage	nSLEEP				0.8	V	
V _{IH}	Input logic high voltage			2.7				
I _{IL}	Input logic low current			V _I = 0.8 V		< 1	10	μA
I _{IH}	Input logic high current			V _I = 2 V		27	50	
CONTROL OUTPUTS (nFAULT)								
V _{OL}	Output logic low voltage	I _O = 1 mA				0.4	V	
DMOS DRIVERS (OUTA, OUTB, SENSE, VPROPI)								
r _{DS(on)}	Output ON resistance	Source driver, I _O = -2.8 A, T _J = 25°C, V _{BB} = 6.5 to 36 V		0.48			Ω	
		Source driver, I _O = -2.8 A, T _J = 125°C, V _{BB} = 8 to 36 V		0.74	0.85			
		Source driver, I _O = -2.8 A, T _J = 125°C, V _{BB} = 6.5 to 8 V		0.74	0.9			
		Sink driver, I _O = 2.8 A, T _J = 25°C, V _{BB} = 6.5 to 36 V		0.35				
		Sink driver, I _O = 2.8 A, T _J = 125°C, V _{BB} = 8 to 36 V		0.52	0.7			
		Sink driver, I _O = 2.8 A, T _J = 125°C, V _{BB} = 6.5 to 8 V		0.52	0.75			
V _(TRIP)	SENSE trip voltage	R _(SENSE) between SENSE and GND		450	500	550	mV	
V _f	Body diode forward voltage	Source diode, I _f = -2.8 A				1.4	V	
		Sink diode, I _f = 2.8 A				1.4		
t _{pd}	Propagation delay time	Input edge to source or sink ON			600		ns	
		Input edge to source or sink OFF			100			
t _{COD}	Crossover delay				500		ns	
G _{D(a)}	Differential amplifier gain	V _{BB} = 8 to 36 V; SENSE = 0.1 to 0.4 V		4.8	5	5.2	V/V	
		V _{BB} = 6.5 to 8 V; SENSE = 0.1 to 0.3 V		4.8		5.2	V/V	
PROTECTION CIRCUITS								

Electrical Characteristics (continued)

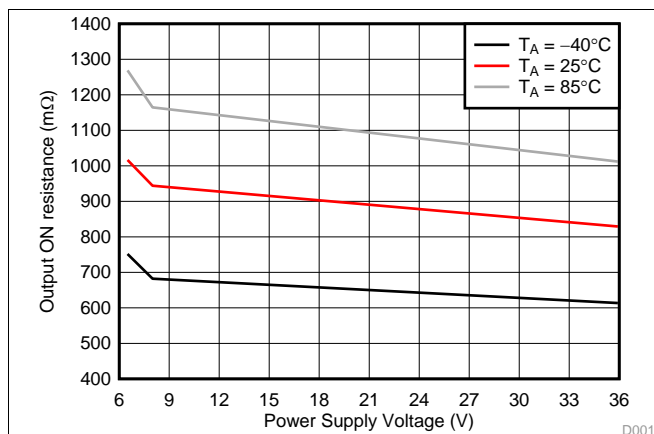
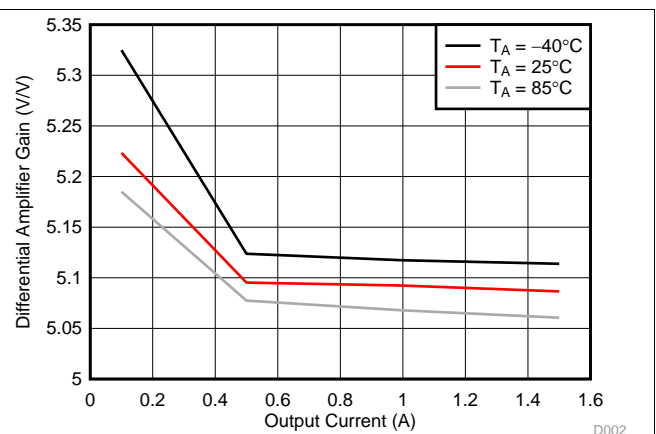
 $T_A = 25^\circ\text{C}$, over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
VUV	UVLO threshold	V_{BB} increasing		5.5	6.4	V
		V_{BB} decreasing			5.7	
	UVLO hysteresis		500		850	mV
$I_{(OCP)}$	Overcurrent protection trip level	$V_{BB} = 8$ to 36 V		3		A
		$V_{BB} = 6.5$ to 8 V		2.8		A
$t_{(DEG)}$	Overcurrent deglitch time			3		μs
$t_{(OCP)}$	Overcurrent retry time		0.5	1.2	3	ms
$T_{(OTW)}$	Thermal warning temperature	Die temperature T_J		160		$^\circ\text{C}$
$T_{\text{hys}(OTW)}$	Thermal warning hysteresis	Die temperature T_J		15		$^\circ\text{C}$
$T_{(OTS)}$	Thermal shutdown temperature	Die temperature T_J		175		$^\circ\text{C}$
$T_{\text{hys}(OTS)}$	Thermal shutdown hysteresis	Die temperature T_J		15		$^\circ\text{C}$

6.6 Dissipation Ratings

PACKAGE	$R_{\theta JA}$	$T_A = 25^\circ\text{C}$ POWER RATING	DERATING FACTOR ABOVE $T_A = 25^\circ\text{C}$
RMJ	36.8	3 W	27 mW/ $^\circ\text{C}$

6.7 Typical Characteristics


Figure 1. $r_{DS(on)}$ Over Voltage

Figure 2. V_{PROPI} Over Output Current

Typical Characteristics (continued)

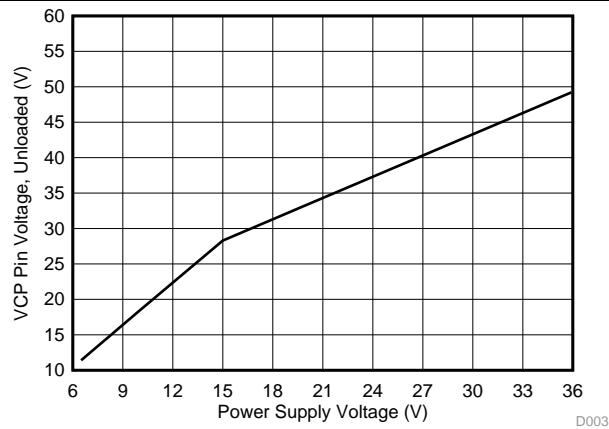


Figure 3. VCP Voltage vs V_{BB}

7 Detailed Description

7.1 Overview

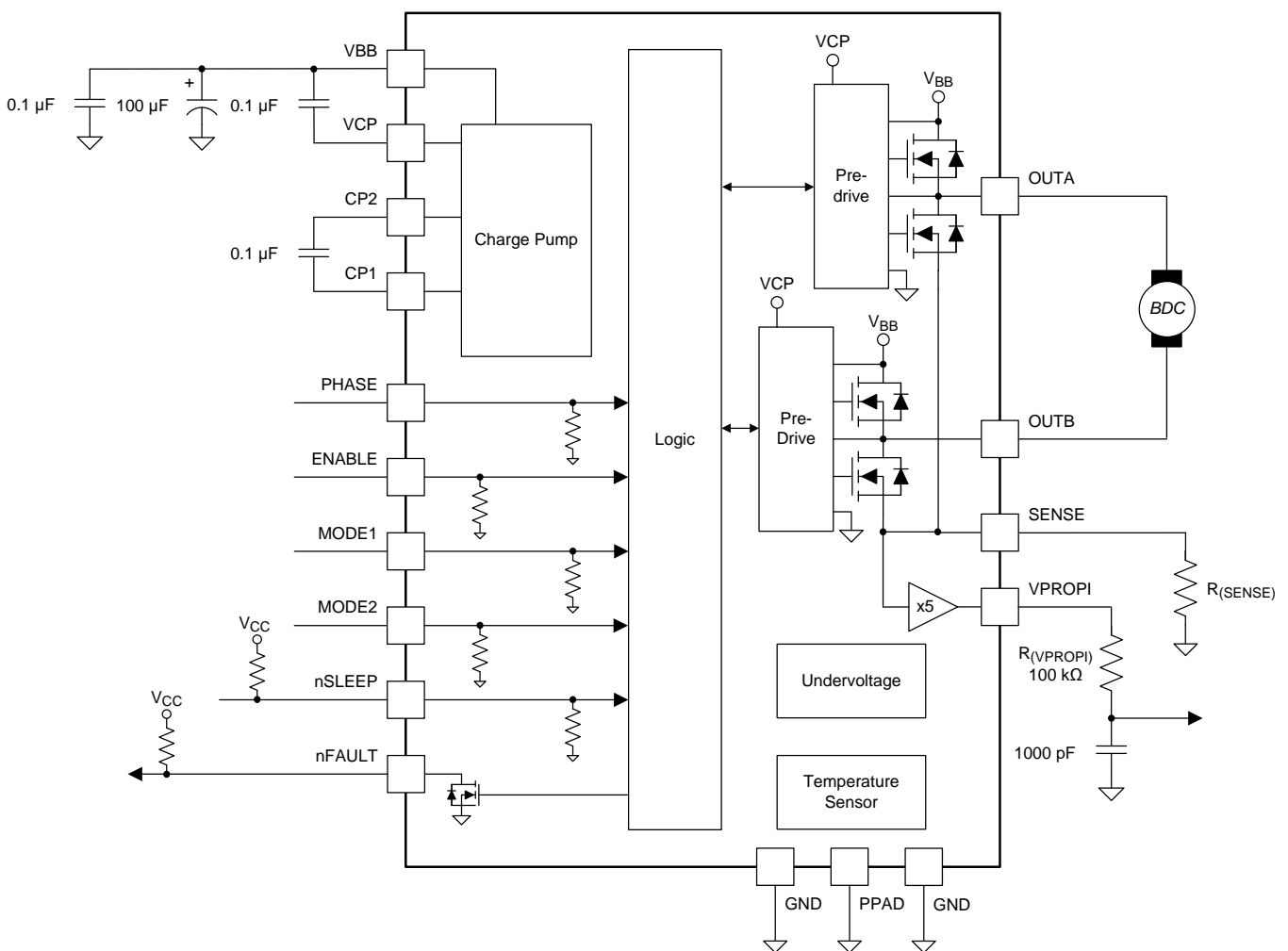
The DRV8801A-Q1 device is an integrated motor driver solutions for brushed-DC motors. The device integrates a DMOS H-bridge and current sense and protection circuitry. The device can be powered with a supply voltage between 6.5 V and 36 V, and is capable of providing an output current up to 2.8-A peak.

A simple PHASE and ENABLE interface allows control of the motor speed and direction.

A shunt amplifier output is provided for accurate current measurements by the system controller. The VPROPI pin outputs a voltage that is five-times the voltage seen at the SENSE pin.

A low-power sleep mode is included which allows the system to save power when not driving the motor.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Power Supervisor

The control input, nSLEEP, is used to minimize power consumption when the DRV8801A-Q1 device is not in use. The nSLEEP input disables much of the internal circuitry, including the internal voltage rails and charge pump. nSLEEP is asserted logic low. A logic high on this input pin results in normal operation. When switching from low to high, the user should allow a 1-ms delay before applying PWM signals. This time is needed for the charge pump to stabilize.

7.3.2 Bridge Control

The following table shows the logic for the DRV8801A-Q1:

nSLEEP	PHASE	ENABLE	MODE1	MODE2	OUTA	OUTB	OPERATION
0	X	X	X	X	Z	Z	Sleep mode
1	0	1	X	X	L	H	Reverse
1	1	1	X	X	H	L	Forward
1	0	0	0	X	H	L	Fast decay
1	1	0	0	X	L	H	Fast decay
1	X	0	1	0	L	L	Low-side Slow decay
1	X	0	1	1	H	H	High-side Slow decay

To prevent reversal of current during fast-decay synchronous rectification, outputs go to the high impedance state as the current approaches 0 A.

The path of current flow for each of the states in the above logic table is shown in [Figure 4](#).

7.3.2.1 MODE 1

Input MODE 1 is used to toggle between fast-decay mode and slow-decay mode. A logic high puts the device in slow-decay mode.

7.3.2.2 MODE 2

MODE 2 is used to select which set of drivers (high side versus low side) is used during the slow-decay recirculation. MODE 2 is meaningful only when MODE 1 is asserted high. A logic high on MODE 2 has current recirculation through the high-side drivers. A logic low has current recirculation through the low-side drivers.

7.3.3 Fast Decay with Synchronous Rectification

This decay mode is equivalent to a phase change where the FETs opposite of the driving FETs are switched on (2 in [Figure 4](#)). When in fast decay, the motor current is not allowed to go negative because this would cause a change in direction. Instead, as the current approaches zero, the drivers turn off. See the [Power Dissipation](#) section for an equation to calculate power.

7.3.4 Slow Decay with Synchronous Rectification (Brake Mode)

In slow-decay mode, both low-side and high-side drivers turn on, allowing the current to circulate through the low-side and high-side body diodes of the H-bridge and the load (3 and 4 in [Figure 4](#)). See the [Power Dissipation](#) section for equations to calculate power for both high-side and low-side slow decay.

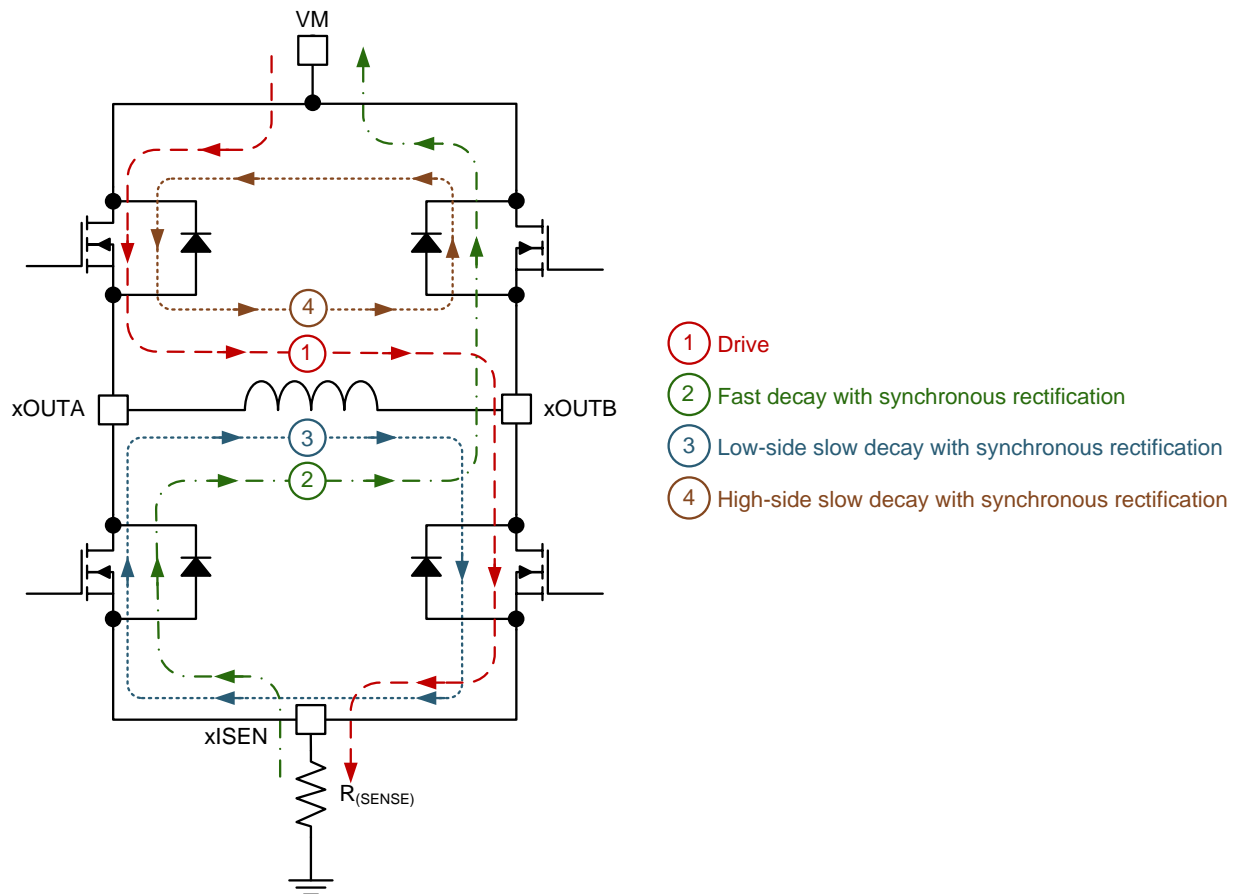


Figure 4. H-Bridge Operation Modes

7.3.5 Charge Pump

The charge pump is used to generate a supply above V_{BB} to drive the source-side DMOS gates. A $0.1\text{-}\mu\text{F}$ ceramic monolithic capacitor should be connected between CP1 and CP2 for pumping purposes. A $0.1\text{-}\mu\text{F}$ ceramic monolithic capacitor should be connected between VCP and V_{BB} to act as a reservoir to run the high-side DMOS devices.

7.3.6 SENSE

A low-value resistor can be placed between the SENSE pin and ground for current-sensing purposes. To minimize ground-trace IR drops in sensing the output current level, the current-sensing resistor should have an independent ground return to the star ground point. This trace should be as short as possible. For low-value sense resistors, the IR drops in the PCB can be significant, and should be taken into account.

To set a manual overcurrent trip threshold, place a resistor between the SENSE pin and GND. When the SENSE pin rises above 500 mV, the H-bridge output is disabled (hi-Z). The device automatically retries with a period of $t_{(OCP)}$.

The overcurrent trip threshold can be calculated using Equation 1.

$$I_{(trip)} = 500 \text{ mV}/R \quad (1)$$

The overcurrent trip level selected cannot be greater than $I_{(OCP)}$.

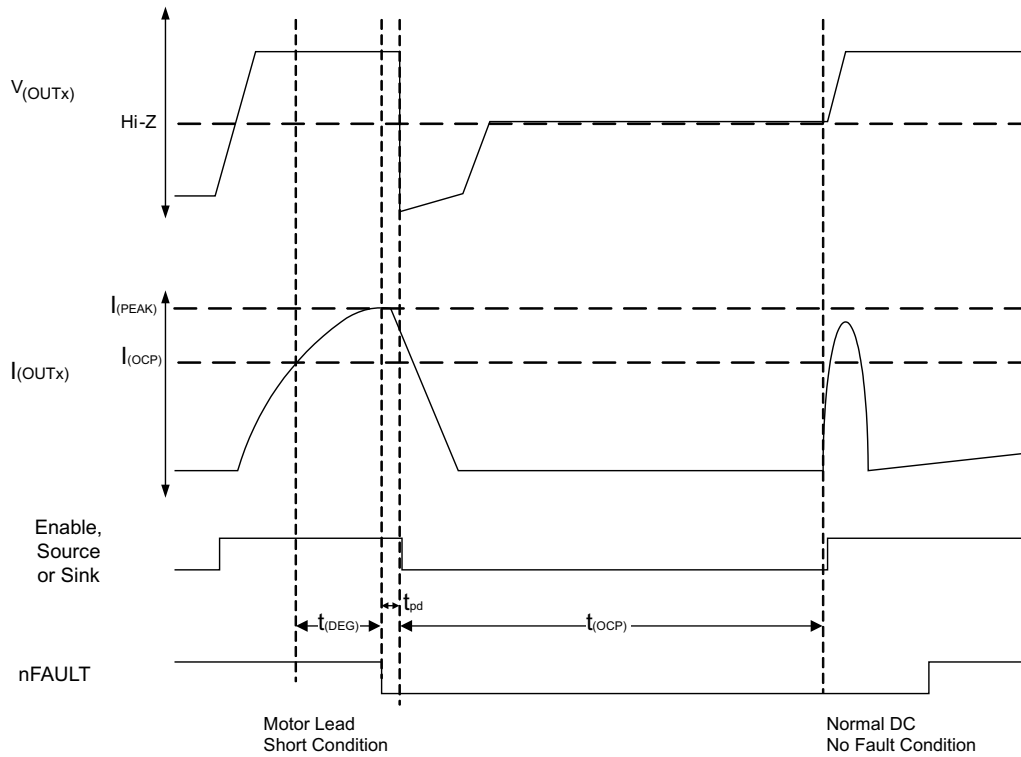


Figure 5. Overcurrent Control Timing

7.3.7 VPROPI

The VPROPI output is equal to approximately five times the voltage present on the SENSE pin. VPROPI is meaningful only if there is a resistor connected to the SENSE pin. If the SENSE pin is connected to ground, VPROPI measures 0 V. Also note that during slow decay (brake), VPROPI measures 0 V. VPROPI can output a maximum of 2.5 V, because at 500 mV on SENSE, the H-bridge is disabled.

7.3.8 Protection Circuits

The DRV8801A-Q1 device is fully protected against V_{BB} undervoltage, overcurrent, and overtemperature events.

FAULT	ERROR REPORT	H-BRIDGE	CHARGE PUMP	RECOVERY
V_{BB} undervoltage (UVLO)	No error report – nFAULT is hi-Z	Disabled	Shut Down	$V_{BB} > V_{UVLO}$ RISING
Overcurrent (OCP)	nFAULT pulled low	Disabled	Operating	Retry time, $t_{(OCP)}$
Overtemperature Warning (OTW)	nFAULT pulled low	Enabled	Operating	$T_J < T_{(OTW)} - T_{hys(OTW)}$
Overtemperature Shutdown (OTS)	nFAULT remains pulled low (set during OTW)	Disabled	Shut Down	$T_J < T_{(OTS)} - T_{hys(OTS)}$

7.3.8.1 V_{BB} Undervoltage Lockout (UVLO)

If at any time the voltage on the V_{BB} pin falls below the undervoltage lockout threshold voltage, all FETs in the H-bridge are disabled and the charge pump is disabled. The nFAULT pin does not report the UVLO fault condition and remains hi-Z. Operation resumes when V_{BB} rises above the UVLO threshold.

7.3.8.2 Overcurrent Protection (OCP)

The current flowing through the high-side and low-side drivers is monitored to ensure that the motor lead is not shorted to supply or ground. If a short is detected, all FETs in the H-bridge are disabled, nFAULT is driven low, and a $t_{(OCP)}$ fault timer is started. After this period, $t_{(OCP)}$, the device is then allowed to follow the input commands and another turn-on is attempted (nFAULT releases during this attempt). If there is still a fault condition, the cycle repeats. If the short condition is not present after $t_{(OCP)}$ expires, normal operation resumes and nFAULT is released.

7.3.8.3 Overtemperature Warning (OTW)

If the die temperature increases past the thermal warning threshold the nFAULT pin is driven low. When the die temperature has fallen below the hysteresis level, the nFAULT pin is released. If the die temperature continues to increase, the device enters overtemperature shutdown as described in the [Overtemperature Shutdown \(OTS\)](#) section.

7.3.8.4 Overtemperature Shutdown (OTS)

If the die temperature exceeds the thermal shutdown temperature, all FETs in the H-bridge are disabled and the charge pump shuts down. The nFAULT pin remains pulled low during this fault condition. When the die temperature falls below the hysteresis threshold, operation automatically resumes.

7.4 Device Functional Modes

The DRV8801A-Q1 device is active unless the nSLEEP pin is brought logic low. In sleep mode the charge pump is disabled and the H-bridge FETs are disabled hi-Z. The DRV8801A-Q1 device is brought out of sleep mode automatically if nSLEEP is brought logic high.

8 Application and Implementation

8.1 Application Information

The DRV8801A-Q1 device is used in medium voltage brushed-DC motor control applications.

8.2 Typical Application

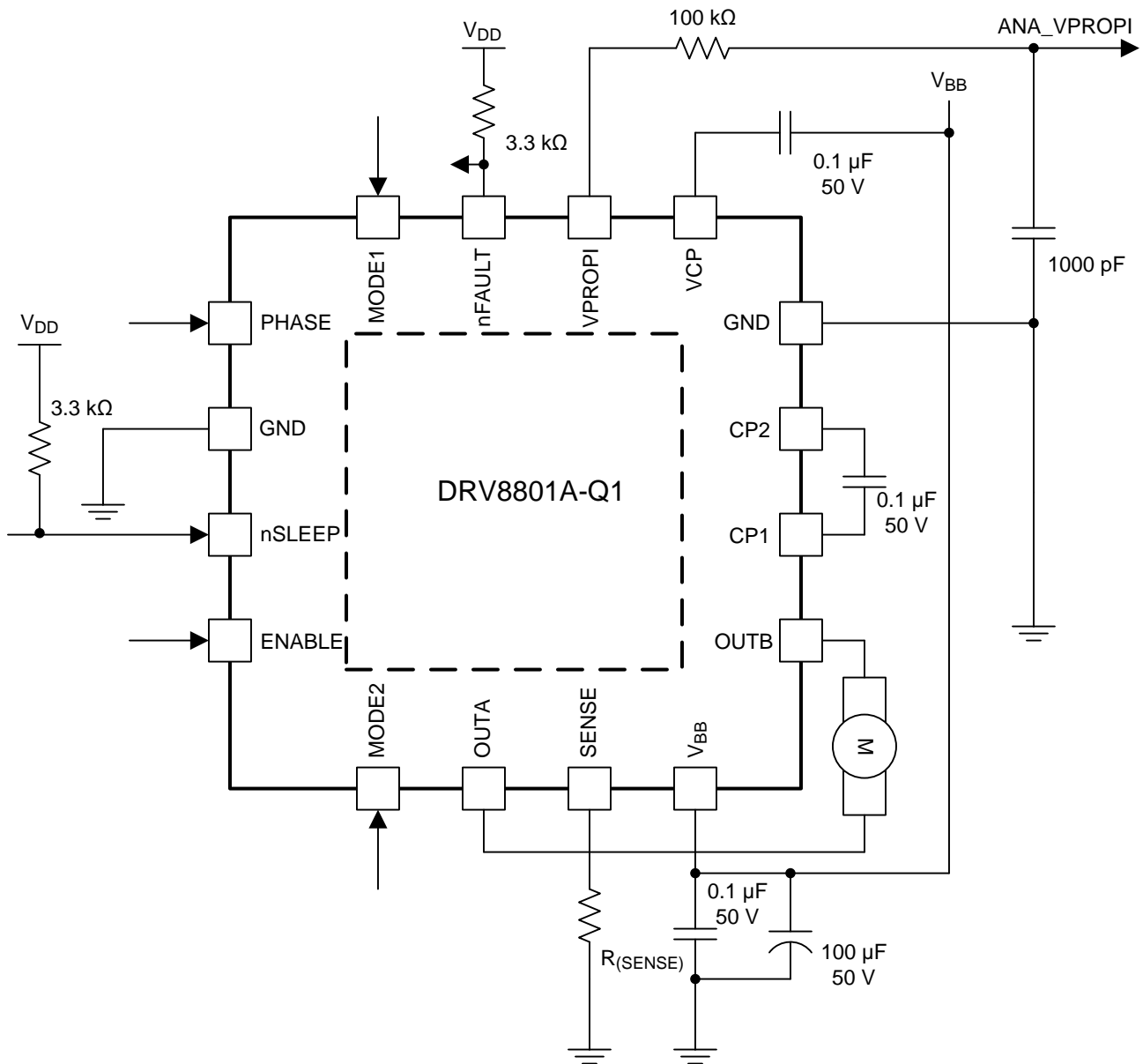


Figure 6. Typical Application Diagram

Typical Application (continued)

8.2.1 Design Requirements

The example supply voltage for this design is $V_{BB} = 18\text{ V}$.

8.2.2 Detailed Design Procedure

8.2.2.1 Drive Current

This current path is through the high-side sourcing DMOS driver, motor winding, and low-side sinking DMOS driver. Power dissipation I^2R losses in one source and one sink DMOS driver, as shown in Equation 2.

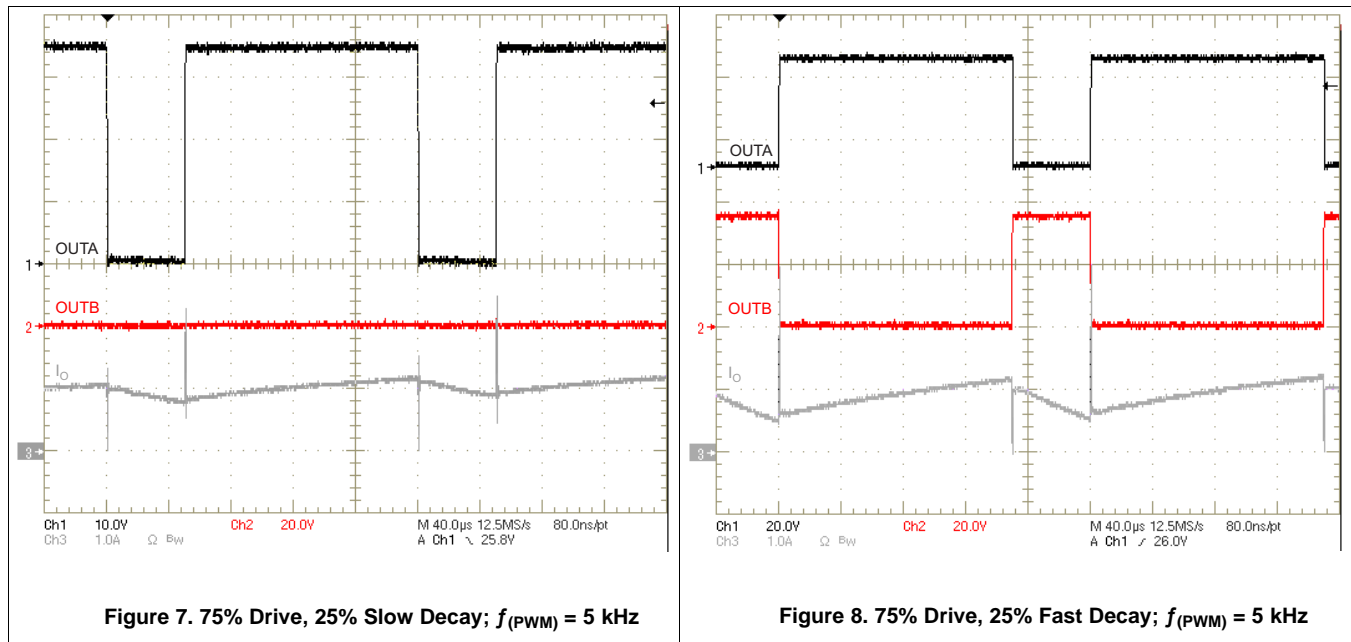
$$P_D = I^2(r_{DS(on)Source} + r_{DS(on)Sink}) \tag{2}$$

8.2.2.2 Slow-Decay SR (Brake Mode)

In slow-decay mode, both low-side sinking drivers turn on, allowing the current to circulate through the low side of the H-bridge (two sink drivers) and the load. Power dissipation I^2R losses in the two sink DMOS drivers as shown in Equation 3

$$P_D = I^2(2 \times r_{DS(on)Sink}) \tag{3}$$

8.2.3 Application Curves



9 Power Supply Recommendations

The DRV8801A-Q1 device is designed to operate from an input-voltage supply (V_{BB}) range between 6.5 V and 36 V. One 0.1- μ F ceramic capacitor rated for V_{BB} must be placed as close as possible to the V_{BB} pin. In addition to the local decoupling caps, additional bulk capacitance is required and must be sized accordingly to the application requirements.

9.1 Bulk Capacitance

Bulk capacitance sizing is an important factor in motor drive system design. This sizing is dependent on a variety of factors including:

- Type of power supply
- Acceptable supply voltage ripple
- Parasitic inductance in the power supply wiring
- Type of motor (brushed DC, brushless DC, stepper)
- Motor startup current
- Motor braking method

The inductance between the power supply and motor drive system will limit the rate current can change from the power supply. If the local bulk capacitance is too small, the system will respond to excessive current demands or dumps from the motor with a change in voltage. Size the bulk capacitance to meet acceptable voltage ripple levels.

The data sheet generally provides a recommended value but system-level testing is required to determine the appropriate sized bulk capacitor.

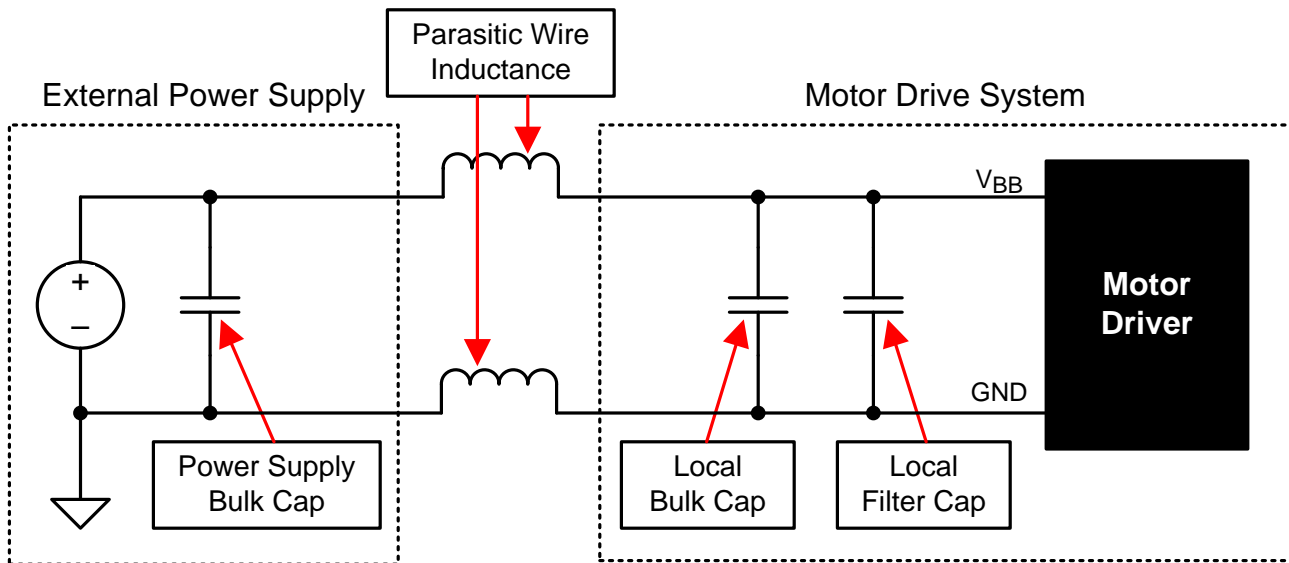


Figure 9. Bulk Capacitance

10 Layout

10.1 Layout Guidelines

The printed circuit board (PCB) should use a heavy ground plane. For optimum electrical and thermal performance, the DRV8801A-Q1 device must be soldered directly onto the board. On the bottom side of the DRV8801A-Q1 device is a thermal pad, which provides a path for enhanced thermal dissipation. The thermal pad should be soldered directly to an exposed surface on the PCB. Thermal vias are used to transfer heat to other layers of the PCB. For more information on this technique, refer to [QFN/SON PCB Attachment](#).

The load supply pin, V_{BB} , should be decoupled with an electrolytic capacitor (typically 100 μF) in parallel with a ceramic capacitor placed as close as possible to the device. In order to minimize lead inductance, the ceramic capacitors between the VCP and V_{BB} pins, connected to the REG pin, and the capacitors between the CP1 and CP2 pins should be as close to the pins of the device as possible.

10.2 Layout Example

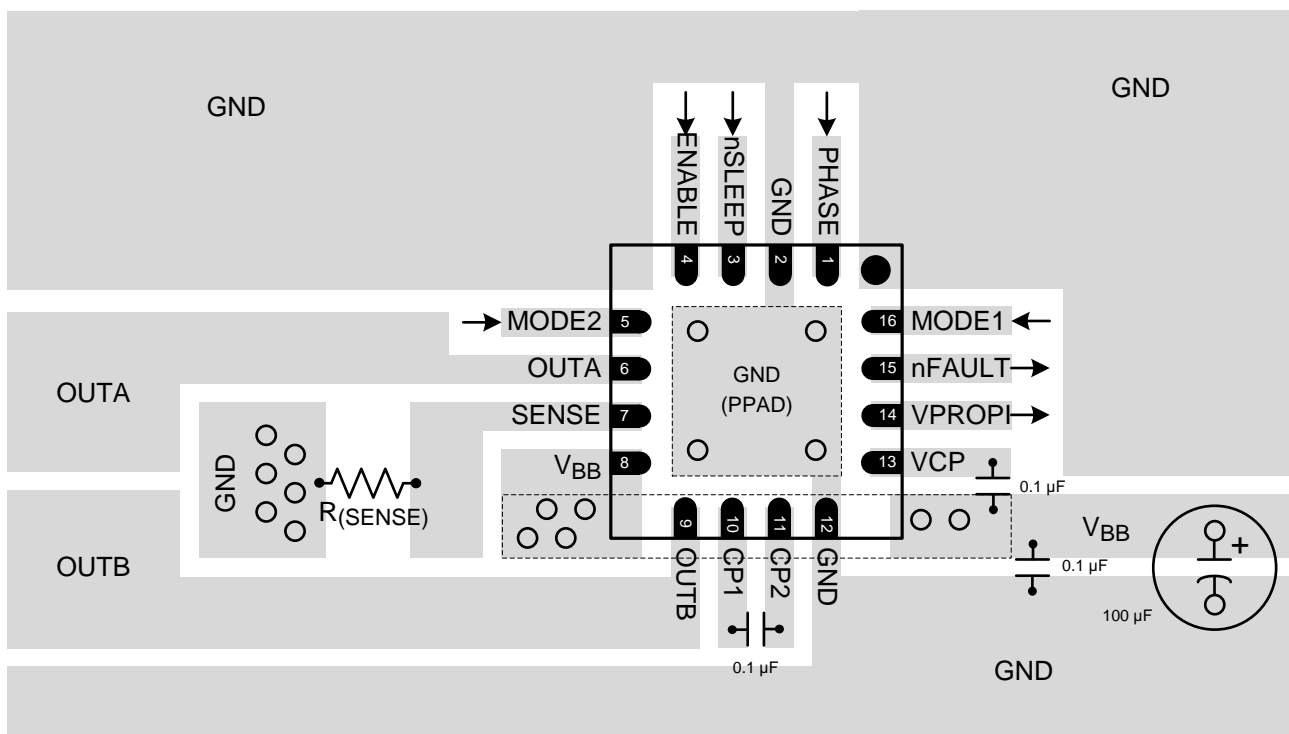


Figure 10. DRV8801A-Q1 Layout

10.3 Power Dissipation

First-order approximation of power dissipation in the DRV8801A-Q1 device can be calculated by examining the power dissipation in the full-bridge during each of the operation modes. The DRV8801A-Q1 device uses synchronous rectification. During the decay cycle, the body diode is shorted by the low- $r_{DS(on)}$ driver, which in turn reduces power dissipation in the full-bridge. In order to prevent shoot through (high-side and low-side drivers on the same side are ON at the same time), the DRV8801A-Q1 device implements a 500-ns typical crossover delay time. During this period, the body diode in the decay current path conducts the current until the DMOS driver turns on. High-current and high-ambient-temperature applications should take this into consideration. In addition, motor parameters and switching losses can add power dissipation that could affect critical applications.

11 Device and Documentation Support

11.1 Documentation Support

11.1.1 Related Documentation

For related documentation, see the following:

[QFN/SON PCB Attachment](#)

11.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of Use](#).

TI E2E™ Online Community *TI's Engineer-to-Engineer (E2E) Community*. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.4 Trademarks

E2E is a trademark of Texas Instruments.
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11.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.6 Glossary

[SLYZ022](#) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, And Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
DRV8801AQRMJRQ1	ACTIVE	WQFN	RMJ	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	DRV8801 ARMJQ1	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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TAPE AND REEL INFORMATION



QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DRV8801AQRMJRQ1	WQFN	RMJ	16	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

TAPE AND REEL BOX DIMENSIONS

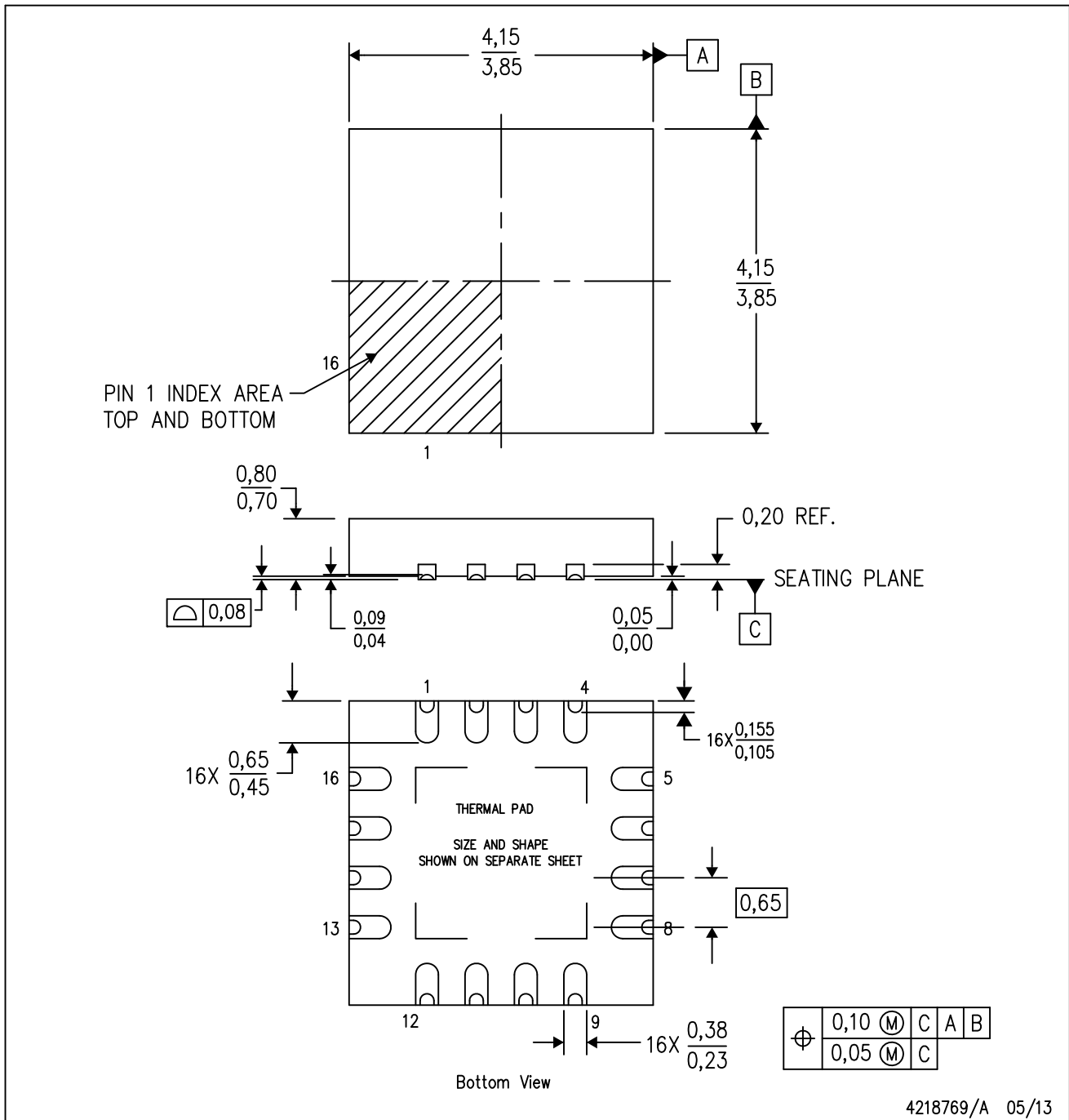


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DRV8801AQRMJRQ1	WQFN	RMJ	16	3000	367.0	367.0	35.0

RMJ (S-PWQFN-N16)

PLASTIC SMALL OUTLINE NO-LEAD



- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. Quad Flatpack, No-leads (QFN) package configuration.
 - D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
 - E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.

THERMAL PAD MECHANICAL DATA

RMJ (S-PWQFN-N16)

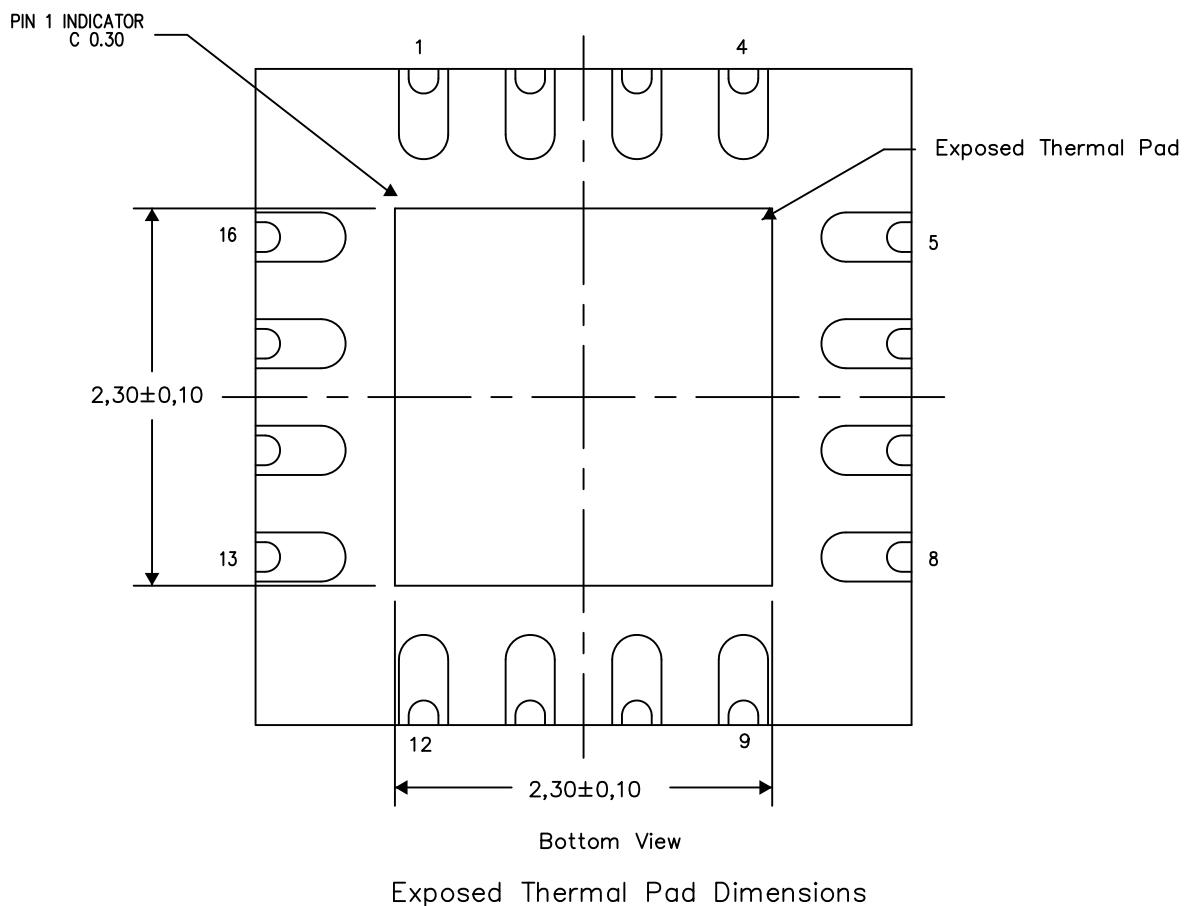
PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



4219300/A 07/13

NOTE: All linear dimensions are in millimeters

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